

**IDS - 12/09/2013 ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

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**Title of  
Invention****SCAN CHAIN DIAGNOSTICS USING LOGIC PATHS**

Application Number : 10/707 373

Confirmation Number :

First Named Applicant: Leendert Huisman

Attorney Docket Number: BUR920030139US1

Art Unit: 2138

Examiner: BRITT

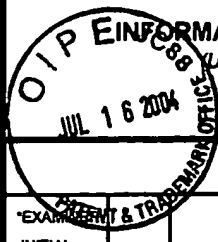
Search string: ( 6308290 ).pn

**US Patent Documents****Note: Applicant is not required to submit a paper copy of cited US Patent Documents**

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
CB	1	6308290	2001-10-23	Forlenza et al.		714	724

**Signature**

Examiner Name	Date
/Cynthia Britt/	07/18/2006



ATTY DOCKET NO. <b>BUR920030139US1</b>		SERIAL NO. <b>10/707373</b>
Leendert M. Huisman et al.		
FILING <b>12/09/2003</b>	GROUP <b>2138</b>	

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

CB		Schafer et al., PARTNER SRLS FOR IMPROVED SHIFT REGISTER DIAGNOSTICS, IEEE VLSI Test Symposium 1992, pages 198-201.

EXAMINER <b>/Cynthia Britt/</b>	DATE CONSIDERED <b>07/18/2006</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.